

Search Notes	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/681,975	SHENGHAO ET AL.
	Examiner	Art Unit
	José V. Chen	3637

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
100	132	11/21/88	JL
	129		
	130		
	131		
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